

Device for measuring reflectance coefficients comprises an optically coupled radiation source, a sample holder, a movable reflector coated with a reflective layer and mounted so as to be movable, and a radiation detector, as well as an input and output cylinder positioned at a 90° angle to each other and at a 45° angle relative to the sample holder. The beginning of the input cylinder is connected to the radiation source, and its end is connected to the sample holder. The beginning of the output cylinder is connected to the sample holder, and its end is connected to the radiation detector, wherein both cylinders are secured within a housing that ensures their immobility. A movable reflector, coated with a reflective layer, is mounted so that it can move parallel to the plane of the sample holder and in sequence with the samples being tested. Additionally, a microcontroller, a data display device, and a control button have been incorporated; the output of the control button is connected to the second input of the microcontroller, whose first input is connected to the output of the radiation detector. The first output of the microcontroller is connected to the input of the radiation source, and its second output is connected to the input of the data display device.